

## Statement of Compliance

## **Requested Part**

12 June 2023	205574	4-1	(Part 1 of 1)
	TE Internal Number:	205574-1	
	Product Description:	SEALING PLUG	
	Part Status:	Active	
	Mil-Spec Certified:	No	
EU	RoHS Directive 2011/65/EU:	Compliant	
This declaration covers EU Directive 2011/65/EU incl. Delegated Directive 2015/863/EU.			
	EU ELV Directive: 2000/53/EC	Compliant	
		No Restricted Materials Above T	hreshold
	EU REACH Regulation: (EC) No. 1907/2006	Current ECHA Candidate List: <b>JAN 2</b> Candidate List Declared Against: <b>JAN</b> Does not contain REACH SVHC	. ,
	Halogen Content:	Not Yet Reviewed for halogen conter	nt
So	lder Process Capability Code:	Not applicable for solder process cap	ability
TE Connectivity Co	rporation		

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The part numbers that TE has identified as EU RoHS compliant have a maximum concentration of 0.1% by weight in homogenous materials for lead, hexavalent chromium, mercury, PBB, PBDE, DBP, BBP, DEHP, DIBP, and 0.01% for cadmium, or qualify for an exemption to these limits as defined in the Annexes of Directive 2011/65/EU (RoHS2). Finished electrical and electronic equipment products will be CE marked as required by Directive 2011/65/EU. Components may not be CE marked.

Additionally, the part numbers that TE has identified as EU ELV compliant have a maximum concentration of 0.1% by weight in homogenous materials for lead, hexavalent chromium, and mercury, and 0.01% for cadmium, or qualify for an exemption to these limits as defined in the Annexes of Directive 2000/53/EC (ELV).

Regarding the REACH Regulation, the information TE provides on SVHC in articles for this part number is based on the latest European Chemicals Agency (ECHA) 'Guidance on requirements for substances in articles' posted at this URL: https://echa.europa.eu/guidance-documents/guidance-on-reach

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This information is provided based on reasonable inquiry of our suppliers and represents our current actual knowledge based on the information they provided. This information is subject to change.